Notice of References Cited

10/571,281	Reexamination MAKUTH ET AL.	
Examiner	Art Unit	
TUVEN T NOUVEN	0000	Page 1 of 1

2832

Applicant(s)/Patent Under

TUYEN T. NGUYEN

Application/Control No.

U.S. PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,950,633	09-2005	Kojima et al.	455/73
*	В	US-4,754,180	06-1988	Kiedrowski, James A.	310/90.5
*	С	US-7,304,559	12-2007	Fortsch et al.	336/234
*	D	US-5,572,178	11-1996	Becker et al.	336/120
*	Е	US-5,347,256	09-1994	Yumiki et al.	336/84C
	F	US-			
	G	US-			
	Н	US-			
	Т	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q		1			
	R					
	s					
	т					

NON DATENT DOCUMENTS

	NON-FAIENT DOCUMENTS		
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
	v		
	w		
	×		

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.